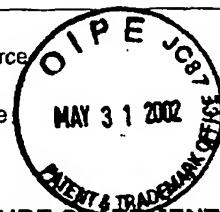


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Applicant: GUI et al.

Appln. No.: 10/043,271

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Page 1 of 1

Examiner: UNKNOWN Group Art Unit: 2851

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
PLC	AR 4,798,470	01/1989	MORIYAMA et al.			
PLC	BR 4,952,060	08/1990	INA et al.			
PLC	CR 5,298,988	03/1994	EVERETT et al.			
PLC	DR 5,361,132	11/1994	FARN			
PLC	ER 5,874,190	02/1999	TANAKA			
PLC	FR 5,929,997	07/1999	LIN			
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
PLC	OR 0 756 207 A3	01/1997	EUROPE	TANAKA et al.		
PLC	PR					
PLC	QR					
PLC	RR					
PLC	SR					

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

PLC	TR	Patent Abstract of Japan, JP11340120, published December 1999
PLC	UR	Patent Abstract of Japan, JP05144702, published June 1993
PLC	VR	Patent Abstract of Japan, JP3246923, published November 1991
PLC	WR	Patent Abstract of Japan, JP1164032, published June 1989
PLC	XR	Katagiri et al., "Novel alignment technique for 0.1-μm lithography using the wafer rear surface and canceling tilt effect," <i>Optical Engineering</i> 32(10):2344-2349 (1993)
PLC	YR	Everett et al., "Aligning lithography on opposite surfaces of a substrate," <i>Applied Optics</i> 31(34):7292-7294 (1992)
	ZR	
	AAR	

Examiner

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
PL	AR 3,752,589	08/1973	Kobayashi			
PL	BR 4,046,985	09/1977	Gates			
PL	CR 5,530,552	06/1996	Mermagen et al.			
PL	DR 5,843,831	12/1998	Chung et al.			
PL	ER 5,894,530	04/1999	Wilt			
PL	FR 5,985,764	11/1999	Lin et al.			
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

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FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
PL	OR 1-164032	06/1989	Japan		X			X
PL	PR 3-246923	11/1991	Japan		X			X
PL	QR 10-187937	07/1998	Japan		X			X
PL	RR 10-209030	08/1998	Japan		X			X
	SR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

TR		
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